

**Search Notes**

Application/Control No.

10/823,229

Examiner

Chapman E. Jeanette

Applicant(s)/Patent under  
Reexamination

TAKEUCHI ET AL.

Art Unit

3635

**SEARCHED**

Class	Subclass	Date	Examiner
52	167.1, 289, 650.1, 736.2		
	737.1		
	236.6		
	655.1		
	714		
403	403,262		
	187,174		
	408.1		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR